#### **X-ray Scattering from Ultrathin Ferroelectrics**





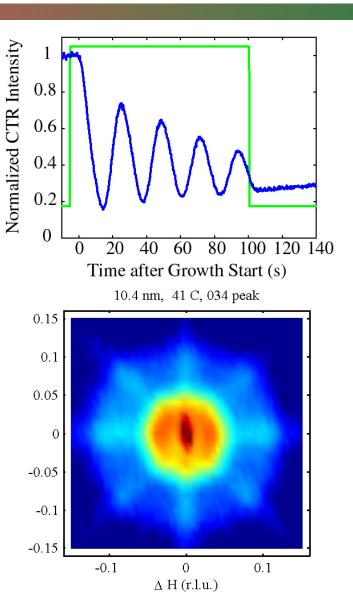
NORTHERN ILLINOIS UNIVERSITY G. B. Stephenson, D. D. Fong,P. H. Fuoss, S. K. Streiffer,O. Auciello, J. A. Eastman,

Materials Science Division, Argonne National Lab

# Carol Thompson

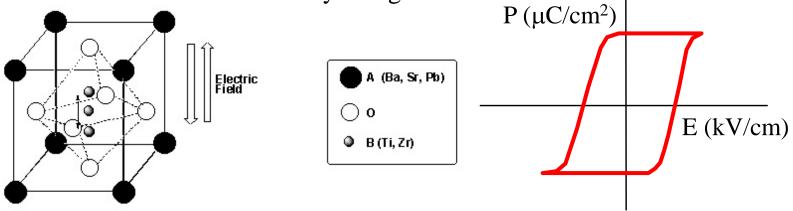
Department of Physics, Northern Illinois Univ.

APS User Monthly Ops Meeting November 18, 2004

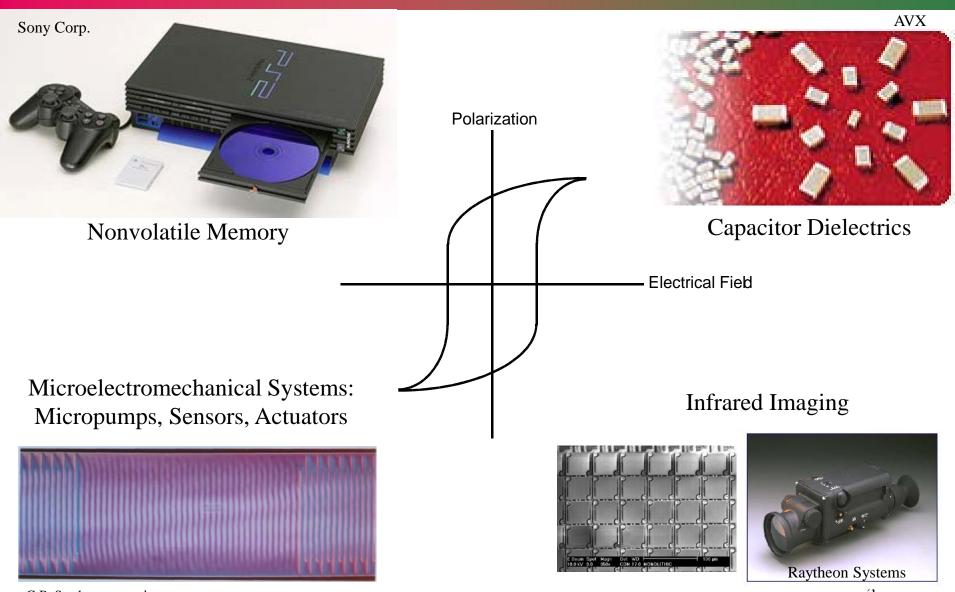


#### **Ferroelectrics vs. Ferromagnets**

- Ferroelectrics are electric analogue of ferromagnets
- Phase transition with polarization as order parameter
- Below T<sub>C</sub>, have spontaneous electric polarization at zero field
- Unit cell of crystal is non-centrosymmetric (charges separated)
- Switchable under application of electric field
- Often form domain structures polarized regions with different orientations
- Differences with magnets: Polarization strongly coupled to strain; field can be neutralized by charge



#### **Ferroelectrics and Technology**



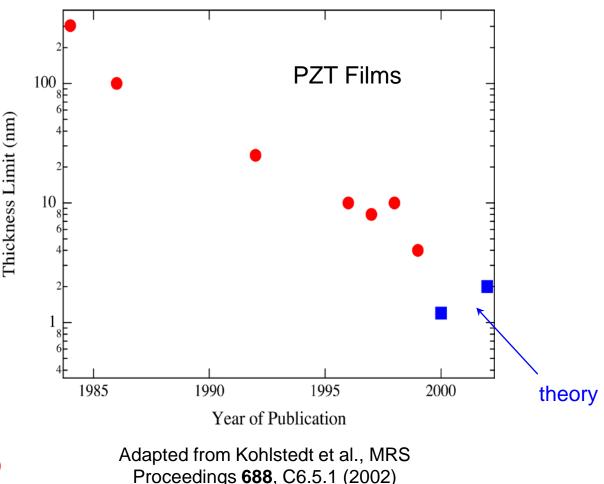
G.B. Stephenson, et al.

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# **Suppression of Ferroelectricity in Thin Films**

- Historically, observed suppression of ferroelectricity in thin films
- What is the cause?
  - extrinsic effects variable stress, composition, defects
  - "intrinsic" surface effect
  - depolarizing field
- What is the ultimate thickness limit, and why? Is *T<sub>c</sub>* suppressed?

See review by T. M. Shaw et al., Annu. Rev. Mater. Sci. **30**, 263 (2000) Thickness Limit for Ferroelectricity vs. Year of Publication

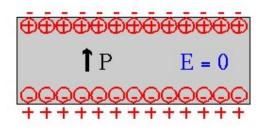


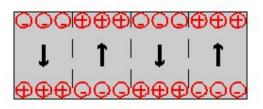
# **Depolarizing Field**

Depolarizing field  $E_D$  is the electric field arising from polarization, which can be partially compensated by

- Free charge at surface/interface from
  - Conducting or semiconducting ferroelectric
  - Conducting or semiconducting electrodes
  - Electrodes with "dead layers"
  - Charged surface adsorbates
- Domain formation

⊕⊕⊕⊕⊕⊕⊕⊕⊕⊕⊕⊕ ↑ P ↓ E ⊖⊖⊖⊖⊖⊖⊖⊖⊖⊖⊖⊖

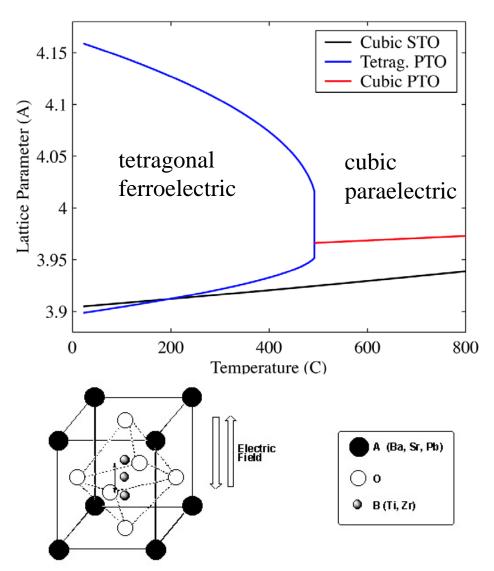




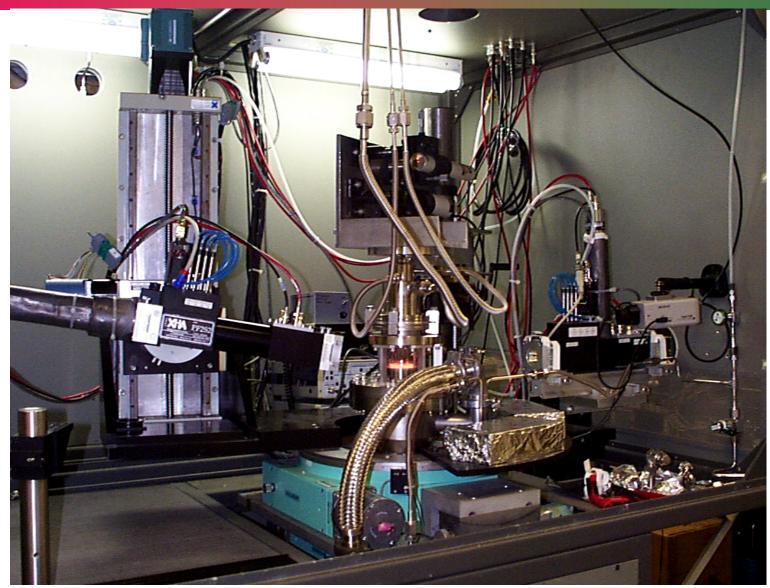
If depolarizing field is uncompensated,  $T_C$  suppression will be equal to the Curie constant *C* (for PbTiO<sub>3</sub>, *C* = 1.5 x 10<sup>5</sup> K)

# Approach

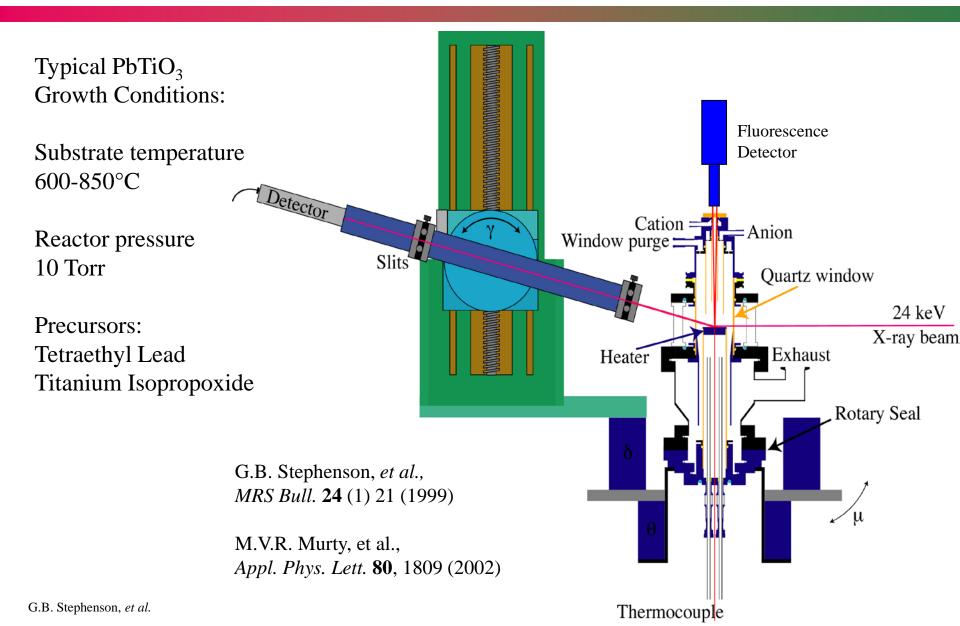
- Use x-ray scattering to study ultrathin films during growth and in-situ as a function of temperature and thickness
- PbTiO<sub>3</sub> is an ideal system -prototypical perovskite ferroelectric, materials properties known
- Control strain state by studying coherently-strained epitaxial films on SrTiO<sub>3</sub>



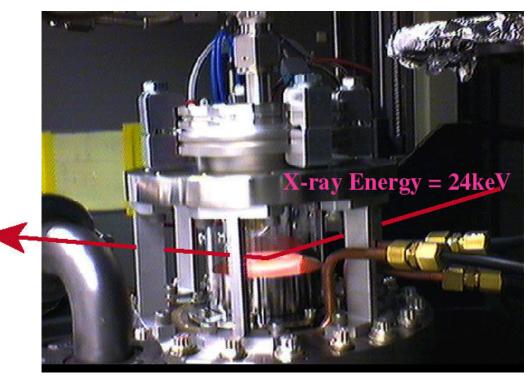
#### In Situ X-ray / Chemical Vapor Deposition Chamber at 12ID



## In Situ X-ray Studies of Chemical Vapor Deposition



### *In-situ* X-ray Characterization of Films Grown by Metal-Organic Chemical Vapor Deposition (MOCVD)

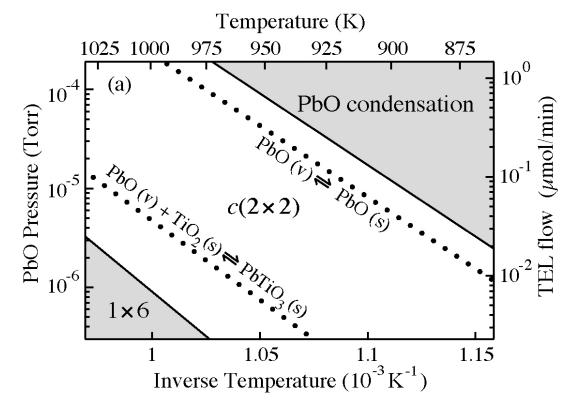


Advanced Photon Source, BESSRC beamline 12ID-D, Argonne National Laboratory

- Films observed in growth chamber
  - Precise control of film thickness to sub-monolayer accuracy
  - Equilibrium vapor pressure controlled over film
    - maintains stoichiometry
    - crucial for studies at high temperature
  - Can study films at high T after growth, avoiding any irreversible relaxation that may occur upon cooling to room T

## **PbTiO<sub>3</sub> Surface Phase Diagram**

- A c( $2\times 2$ ) reconstruction is the equilibrium surface structure across the entire PbTiO<sub>3</sub> single-phase field.
- A poorly ordered  $(1 \times 6)$ reconstruction is observed at PbO pressures below the PbTiO<sub>3</sub> stability line, and is believed to be a nonequilibrium Ti-rich structure.



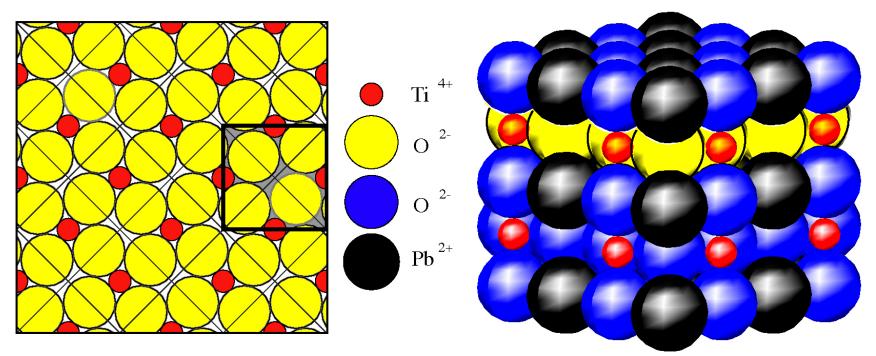
A. Munkholm et al., Phys. Rev. Lett. 88, 016101 (2002).

# **Equilibrium Surface Structure of PbTiO<sub>3</sub>**

## $c(2 \times 2)$ Reconstruction

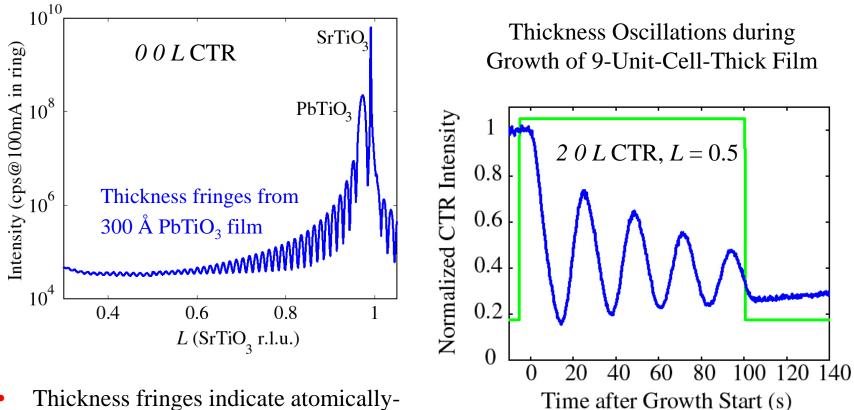
A. Munkholm *et al.*, *PRL* **88**, 016101 (2002).

The equilibrium surface is a PbO-terminated, single-unit-cell layer with an antiferrodistortive structure, obtained by 10° oxygen octahedral rotations. *This reconstruction occurs on films of all thicknesses down to a single unit cell.* 



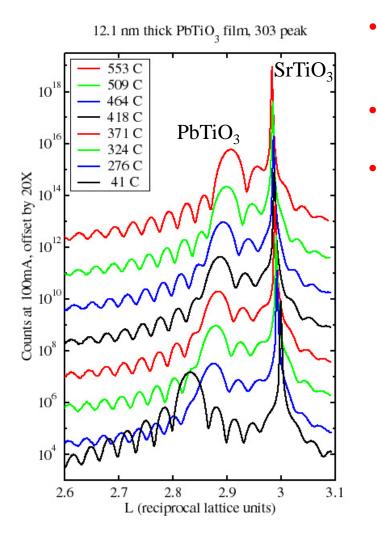
This reconstruction now found in *ab intio* calculations by C. Bungaro *et al.*, cond-mat/0410375 (2004)

#### **Thickness Control to Sub-Unit-Cell Accuracy**

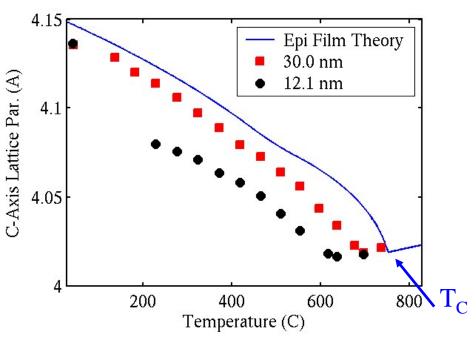


- Thickness fringes indicate atomicallysmooth intefaces
- Can monitor initial growth by observing formation of thickness fringes
- Period of oscillations depends on L; at L = 0.5, period corresponds to 2 unit cells

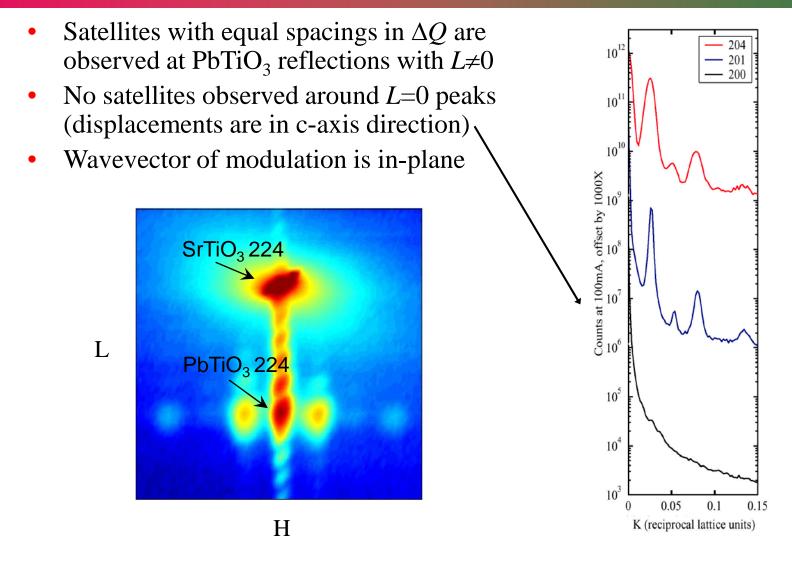
#### **Determination of T<sub>C</sub> from** *c***-Axis Lattice Parameter**



- Ferroelectric phase transition identified by measuring lattice parameter of  $PbTiO_3$  as function of temperature
- Phase transition is continuous, as predicted by theory for epitaxial film
- $T_C$  is elevated less than thick-film prediction, and depends on thickness



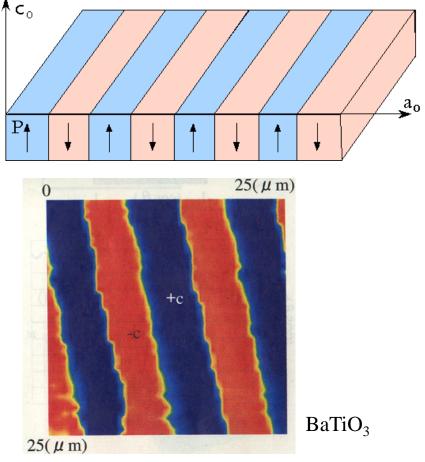
# In-Plane Satellite Peaks Observed 🖊 180° Stripe Domains



S.K. Streiffer et al., PRL 89, 067601 (2002)

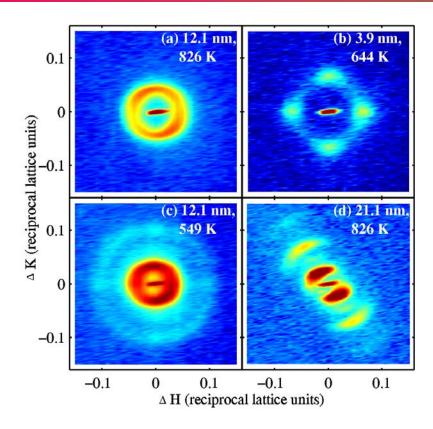
## **180° Stripe Domains in Ferroelectrics**

- 180-degree stripe domains: lamella with alternating polarity
- Experimentally observed in bulk ferroelectrics (e.g., BaTiO<sub>3</sub>), but no previous reports of their detection in thin films
- Associated with minimization of the electric field energy ("depolarizing field")
- Often assumed that film conductivity is high enough to suppress stripe domain formation

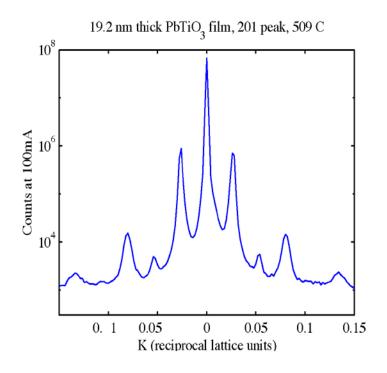


Y. Cho et al., Jpn. J. Appl. Phys., 38, 5689 (1999)

#### **Nanoscale 180° Stripe Domains**



- See various alignments of stripes from in-plane diffraction
- When non-crystallographically aligned, stripes are parallel to miscut steps



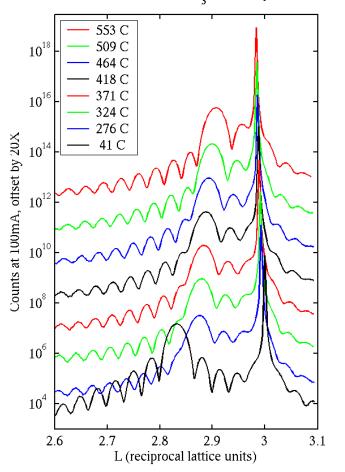
- Under some conditions, see high-order harmonics
- Odd orders strongest ⇒ 50:50 ratio of up/down

S.K. Streiffer et al., PRL 89, 067601 (2002)

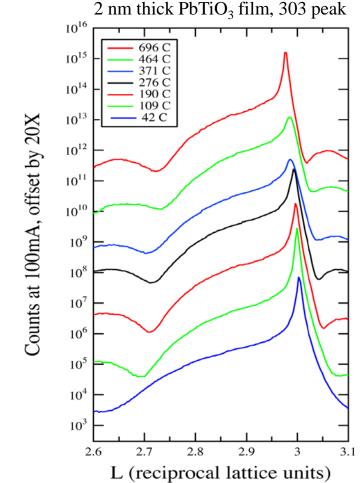
#### Finding T<sub>C</sub> in Ultrathin Films: *c*-axis Lattice Parameter is Difficult to Extract

#### thin film

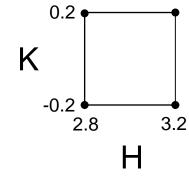
12.1 nm thick PbTiO<sub>3</sub> film, 303 peak

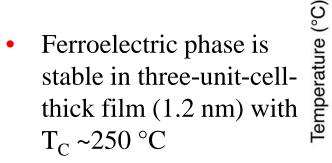


#### ultrathin film

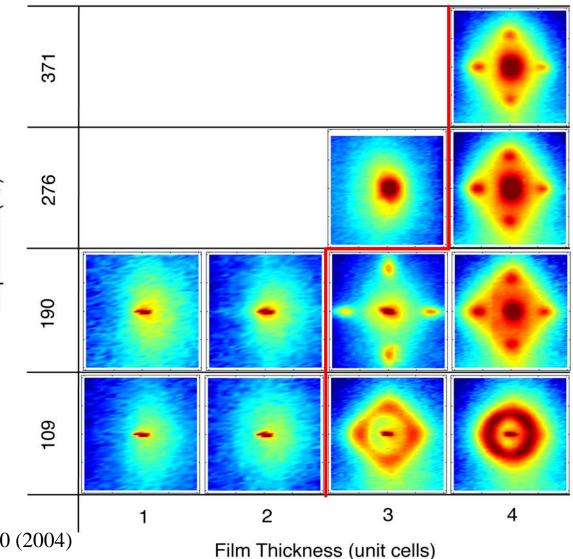


# **Finding T<sub>C</sub> in Ultrathin Films: Onset of Satellites**



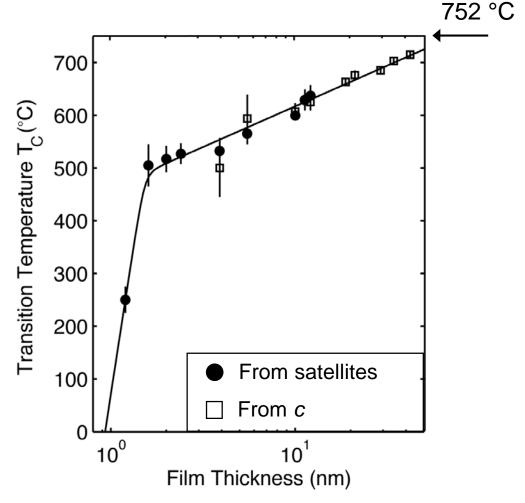


 Ex situ x-ray measurements at -153 °C found no ferroelectric transition in 2 unit cell sample



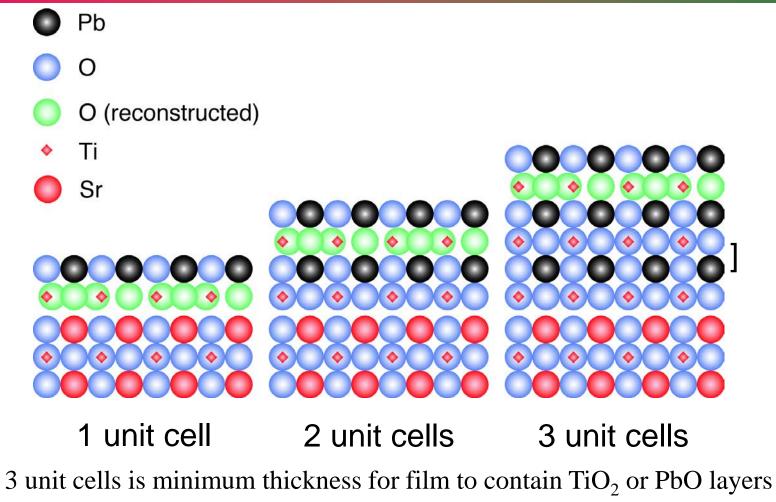
#### **Dependence of T<sub>C</sub> on Film Thickness**

- T<sub>C</sub> determined from onset of stripes agrees with that from lattice parameter
- See gradual decrease, then abrupt drop in T<sub>C</sub> at 3 unit cells
- What causes dependence of T<sub>C</sub> on film thickness?



D.D. Fong et al., Science 304, 1650 (2004)

# Why is 3-Unit-Cell Thickness Required for Ferroelectricity?



D.D. Fong et al., Science 304, 1650 (2004)

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## **Conclusions and Outlook**

- *In situ* x-ray scattering studies provide understanding of synthesis and phase transitions in ultrathin ferroelectrics
  - Equilibrium surface structure of PbTiO<sub>3</sub>
  - MOCVD growth mechanisms
  - Sub-monolayer thickness control
  - Nanoscale thickness effects on phase stability
  - 180° stripe domain formation
  - Effects of mechanical and electrical boundary conditions
- Competition between polarization, depolarizing field, epitaxial strain, domain formation, intrinsic surface effects, and interface compensation by charged species produce unexpectedly rich behavior in ultrathin ferroelectric films
- We have just begun to understand these phenomena to the point where we can predict and control them